

LIST OF ART CITED BY APPLICANT

(PTO-1449)

 ATTY. DOCKET NO.
K-0195B

 APPLN. SERIAL NO.
10/669.445

 APPLICANT(S)
Jae Kyum KIM et al.

 FILING DATE
September 25, 2003

 GROUP
3729

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
EC	4,623,812	11/18/1986	Van de Griend	310	268	3/6/1985
I	4,712,035	12/8/1987	Forbes et al.	310	269	11/12/1985
I	5,150,589	9/29/1992	Williams et al.	68	23.7	6/4/1991
I	5,266,855	11/30/1993	Smith et al.	310	90	8/14/1990
EC	5,737,944	4/14/1998	Nishimura et al.	68	23.7	9/11/1996

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

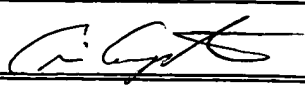
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	WO 98/56973	12/17/1998	WIPO			AB	
EC	WO 98/56974	12/17/1998	WIPO			AB	
EC	WO 98/59102	12/30/1998	WIPO			AB	
EC	DE 1907719	8/13/1970	Germany			X	
EC	1020000077232	12/26/2000	Korea			AB	
EC	462765	12/28/1966	Swiss			X	
EC	JP5176488	7/13/1993	Japan			AB	
EC	JP11028298	2/2/1999	Japan			AB	
EC	JP10210727	8/7/1998	Japan			AB	
EC	JP9098547	4/8/1997	Japan			AB	
EC	JP4033536	2/4/1992	Japan			AB	
EC	JP59035548	2/27/1984	Japan			AB	
EC	JP61236350	10/21/1986	Japan			AB	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER



DATE CONSIDERED

9/27/05

SHEET 1

LIST OF PRIOR ART CITED BY
APPLICANT
(PTO-1449)

ATTY. DOCKET NO.
K-195B

APPLN. SERIAL NO.
10/669,445

APPLICANT(S)
Jae Kyum KIM et al.

CUSTOMER NO. 34610

FILING DATE
September 25, 2003

GROUP
To be Assigned

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	.

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EJ	JP2000-325693	11/28/2000	Japan (abstract & full text)				
{C	JP2000-334194	12/5/2000	Japan (abstract & full text)				
EC	KR2000-77232	12/26/2000	Korea (abstract & full text)				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

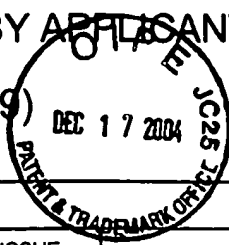
EXAMINER

DATE CONSIDERED

9/27/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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LIST OF ART CITED BY APPLICANT (PTO-1449)				ATTY. DOCKET NO. K-0195B		APPLN. SERIAL NO. 10/669,445	
				APPLICANT(S) Jae Kyum KIM et al.			
				FILING DATE 9/25/2003		GROUP 3729	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
EC	3,248,908	5/1966	Pope, Ian M.				
	3,604,222	9/1971	Wutherich et al.				
	3,840,764	10/1974	Burger, Manfred				
	4,446,706	5/1984	Hartwig, Carl. S.M.				
	4,853,571	8/1989	Smith et al.				
	4,998,052	3/1991	Erdman et al.				
	5,040,285	8/1991	Williams et al.				
	5,150,589	9/1992	Williams et al.				
	5,737,944	4/1998	Nishimura et al.				
	5,894,746	4/1999	Skrippek, Jorg				
EC	5,975,846	11/1999	Wistinghausen, Walter				
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	JP 11-137884	5/25/99	JAPAN			AB	
EC	JP 09-103596	4/22/97	JAPAN			AB	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EC	European Patent Specification 219,115 (4/1987)						
EC	European Search Report for EP 04 07 7356						
EXAMINER	Eric [Signature]			DATE CONSIDERED 2/27/05			

DYK/JCE/SSK:knv

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LIST OF PRIOR ART CITED BY APPLICANT (PTO-1449)				ATTY. DOCKET NO. K-195B		APPLN. SERIAL NO. New U.S. Patent Application	
				APPLICANT(S) Jae Kyum KIM, Ho Cheol KWON, Jon A. PARK and Kang Mo CHOI			
				FILING DATE September 25, 2003		GROUP To be assigned	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
EC	5,862,686	01/26/1999	Skippek	68	140		
	5,809,809	09/1998	Neumann	68	140		
	5,996,379	12/1999	Skippek	68	140		
	6,050,113	04/2000	Skippek et al.	68	140		
	6,131,422	10/2000	Skippek et al.	68	140		
	6,148,647	11/2000	Kabeya et al.	68	140		
EC	6,341,507	01/2002	Rode et al.	68	140x		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	JP 11-28298	11/21/2000	Japan				
EC	JP 11-89198	03/30/1999	Japan				
EC	JP 61-17877		Japan				
EC	JP 2-14278		Japan				
EC	JP 11-207077	08/03/1999	Japan				
EC	JP 7-259866	11/19/1996	Japan				
EC	JP 5-176488	07/13/1993	Japan				
EC	JP 11-285205	10/15/1999	Japan				
EC	DE4335966A1	04/27/1995	Germany				
EC	DE19724475A1	12/07/1999	Germany				
EC	WO 98/36123	08/20/1998	Europe				
EC	EP 0620308A2	10/19/1994	Europe				
EC	2333300	7/1999	GREAT BRITAIN				
EC	WO 98/00902	01/08/1998	Europe				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Eric L. [Signature]</i>				DATE CONSIDERED <i>9/27/05</i>			

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